

Notice of References Cited	Application/Control No. 10/510,079	Applicant(s)/Patent Under Reexamination LIN, CHIN-HSI	
	Examiner VanThu Nguyen	Art Unit 2824	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,608,773 B2	08-2003	Lowrey et al.	365/100
	B	US-6,462,982 B1	10-2002	Numata et al.	365/158
	C	US-6,324,090 B1	11-2001	Kang, Hee Bok	365/143
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003281882 A	10-2003	Japan	KANG et al.	G11C 11/22
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.